## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination | HAN ET AL. | Examiner | Art Unit | Page 1 of 1 U.S. PATENT DOCUMENTS \* | Document Number | Date | Country Code-Number-Kind Code | MM-YYYY | Name | Classification | Classification | Classification | Classification | Control No. | Applicant(s)/Patent Under Reexamination | HAN ET AL. | Page 1 of 1

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